Product Preview

64K x 32 Bit Pipelined BurstRAM Synchronous Fast Static RAM

The MCM63P631A is a 2M bit synchronous fast static RAM designed to provide a burstable, high performance, secondary cache for the 68K Family, PowerPC™, and Pentium™ microprocessors. It is organized as 64K words of 32 bits each. This device integrates input registers, an output register, a 2–bit address counter, and high speed SRAM onto a single monolithic circuit for reduced parts count in cache data RAM applications. Synchronous design allows precise cycle control with the use of an external clock (K). CMOS circuitry reduces the overall power consumption of the integrated functions for greater reliability.

Addresses (SA), data inputs (DQx), and all control signals except output enable (\overline{G}) , sleep mode (ZZ), and Linear Burst Order (\overline{LBO}) are clock (K) controlled through positive–edge–triggered noninverting registers.

Bursts can be initiated with either $\overline{\text{ADSP}}$ or $\overline{\text{ADSC}}$ input pins. Subsequent burst addresses can be generated internally by the MCM63P631A (burst sequence operates in linear or interleaved mode dependent upon state of $\overline{\text{LBO}}$) and controlled by the burst address advance $(\overline{\text{ADV}})$ input pin.

Write cycles are internally self–timed and are initiated by the rising edge of the clock (K) input. This feature eliminates complex off–chip write pulse generation and provides increased timing flexibility for incoming signals.

Synchronous byte write (\overline{SBx}) , synchronous global write (\overline{SGW}) , and synchronous write enable \overline{SW} are provided to allow writes to either individual bytes or to all bytes. The four bytes are designated as "a", "b", "c", and "d". \overline{SBa} controls DQa, \overline{SBb} controls DQb, etc. Individual bytes are written if the selected byte writes \overline{SBx} are asserted with \overline{SW} . All bytes are written if either \overline{SGW} is asserted or if all \overline{SBx} and \overline{SW} are asserted.

For read cycles, pipelined SRAMs output data is temporarily stored by an edge—triggered output register and then released to the output buffers at the next rising edge of clock (K).

The MCM63P631A operates from a 3.3 V power supply, all inputs and outputs are LVTTL compatible.

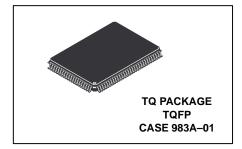
- MCM63P631A-117 = 4.5 ns access / 8.5 ns cycle (117 MHz)
 MCM63P631A-100 = 4.5 ns access / 10 ns cycle (100 MHz)
 MCM63P631A-75 = 7 ns access / 13.3 ns cycle (75 MHz)
 MCM63P631A-66 = 8 ns access / 15 ns cycle (66 MHz)
- Single 3.3 V + 10%, 5% Power Supply
- ADSP, ADSC, and ADV Burst Control Pins
- Selectable Burst Sequencing Order (Linear/Interleaved)
- Internally Self-Timed Write Cycle
- Byte Write and Global Write Control
- Sleep Mode (ZZ)
- PB1 Version 2.0 Compatible
- Single-Cycle Deselect Timing
- JEDEC Standard 100-Pin TQFP Package

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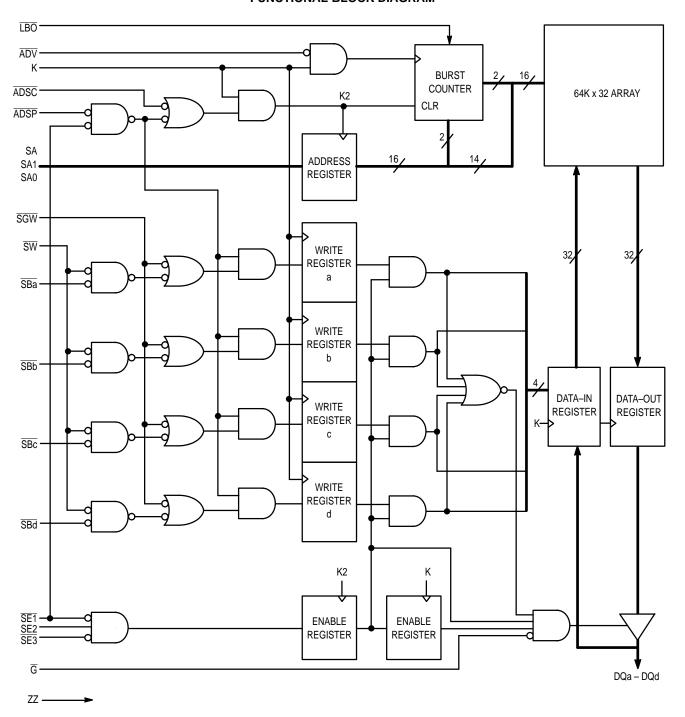
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MCM63P631A

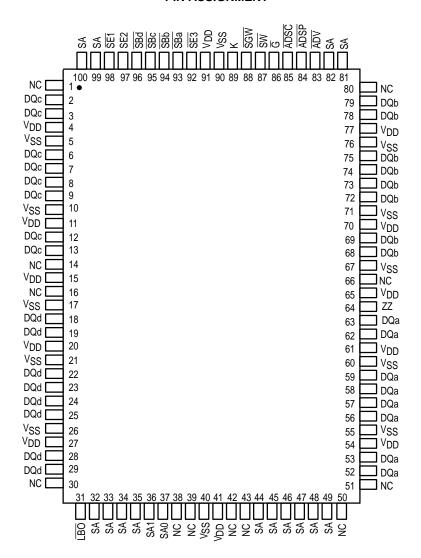




FUNCTIONAL BLOCK DIAGRAM



PIN ASSIGNMENT



PIN DESCRIPTIONS

Pin Locations	Symbol	Type	Description
85	ADSC	Input	Synchronous Address Status Controller: Active low, is used to latch a new external address. Used to initiate a READ, WRITE or chip deselect.
84	ADSP	Input	Synchronous Address Status Processor: Initiates READ or chip deselect cycle (exception — chip deselect does not occur when ADSP is asserted and SE1 is high).
83	ĀDV	Input	Synchronous Address Advance: Increments address count in accordance with counter type selected (linear/interleaved).
(a) 52, 53, 56, 57, 58, 59, 62, 63 (b) 68, 69, 72, 73, 74, 75, 78, 79 (c) 2, 3, 6, 7, 8, 9, 12, 13 (d) 18, 19, 22, 23, 24, 25, 28, 29	DQx	I/O	Synchronous Data I/O: "x" refers to the byte being read or written (byte a, b, c, d).
86	G	Input	Asynchronous Output Enable.
89	К	Input	Clock: This signal registers the address, data in, and all control signals except \overline{G} , \overline{LBO} , and ZZ.
31	LBO	Input	Linear Burst Order Input: This pin must remain in steady state (this signal not registered or latched). It must be tied high or low. Low — linear burst counter (68K/PowerPC). High — interleaved burst counter (486/i960/Pentium).
32, 33, 34, 35, 44, 45, 46, 47, 48, 49, 81, 82, 99, 100	SA	Input	Synchronous Address Inputs: These inputs are registered and must meet setup and hold times.
36, 37	SA1, SA0	Input	Synchronous Address Inputs: These pins must be wired to the two LSBs of the address bus for proper burst operation. These inputs are registered and must meet setup and hold times.
93, 94, 95, 96 (a) (b) (c) (d)	SBx	Input	Synchronous Byte Write Inputs: "x" refers to the byte being written (byte a, b, c, d). \$\overline{SGW}\$ overrides \$\overline{SBx}\$.
98	SE1	Input	Synchronous Chip Enable: Active low to enable chip. Negated high — blocks ADSP or deselects chip when ADSC is asserted.
97	SE2	Input	Synchronous Chip Enable: Active high for depth expansion.
92	SE3	Input	Synchronous Chip Enable: Active low for depth expansion.
88	SGW	Input	Synchronous Global Write: This signal writes all bytes regardless of the status of the SBx and SW signals. If only byte write signals SBx are being used, tie this pin high.
87	SW	Input	Synchronous Write: This signal writes only those bytes that have been selected using the byte write \overline{SBx} pins. If only byte write signals \overline{SBx} are being used, tie this pin low.
64	ZZ	Input	Sleep Mode: This active high asynchronous signal places the RAM into the lowest power mode. The ZZ pin disables the RAMs internal clock when placed in this mode. When ZZ is negated, the RAM remains in low power mode until it is commanded to READ or WRITE. Data integrity is maintained upon returning to normal operation.
4, 11, 15, 20, 27, 41, 54, 61, 65, 70, 77, 91	V _{DD}	Supply	Power Supply: 3.3 V + 10%, – 5%.
5, 10, 17, 21, 26, 40, 55, 60, 67, 71, 76, 90	VSS	Supply	Ground.
1, 14, 16, 30, 38, 39, 42, 43, 50, 51, 66, 80	NC	_	No Connection: There is no connection to the chip.

TRUTH TABLE (See Notes 1 through 5)

Next Cycle	Address Used	SE1	SE2	SE3	ADSP	ADSC	ADV	<u>G</u> 3	DQx	Write 2, 4
Deselect	None	1	Х	Х	Х	0	Х	Х	High–Z	Х
Deselect	None	0	Х	1	0	Х	Х	Х	High–Z	Х
Deselect	None	0	0	Х	0	Х	Х	Х	High–Z	Х
Deselect	None	Х	Х	1	1	0	Х	Х	High–Z	Х
Deselect	None	Х	0	Х	1	0	Х	Х	High–Z	Х
Begin Read	External	0	1	0	0	Х	Х	Х	High–Z	READ ⁵
Begin Read	External	0	1	0	1	0	Х	Х	High–Z	READ ⁵
Continue Read	Next	Х	Х	Х	1	1	0	1	High–Z	READ
Continue Read	Next	Х	Х	Х	1	1	0	0	DQ	READ
Continue Read	Next	1	Х	Х	Х	1	0	1	High–Z	READ
Continue Read	Next	1	Х	Х	Х	1	0	0	DQ	READ
Suspend Read	Current	Х	Х	Х	1	1	1	1	High–Z	READ
Suspend Read	Current	Х	Х	Х	1	1	1	0	DQ	READ
Suspend Read	Current	1	Х	Х	Х	1	1	1	High–Z	READ
Suspend Read	Current	1	Х	Х	Х	1	1	0	DQ	READ
Begin Write	External	0	1	0	1	0	Х	Х	High–Z	WRITE
Continue Write	Next	Х	Х	Х	1	1	0	Х	High–Z	WRITE
Continue Write	Next	1	Х	Х	Х	1	0	Х	High–Z	WRITE
Suspend Write	Current	Х	Х	Х	1	1	1	Х	High–Z	WRITE
Suspend Write	Current	1	Х	Х	Х	1	1	Х	High–Z	WRITE

NOTES:

- 1. X = Don't Care. 1 = logic high. 0 = logic low.
- 2. Write is defined as either 1) any \overline{SBx} and \overline{SW} low or 2) \overline{SGW} is low.
- 3. \overline{G} is an asynchronous signal and is not sampled by the clock K. \overline{G} drives the bus immediately (t_{GLQX}) following \overline{G} going low.
- 4. On write cycles that follow read cycles, \overline{G} must be negated prior to the start of the write cycle to ensure proper write data setup times. \overline{G} must also remain negated at the completion of the write cycle to ensure proper write data hold times.

5. This READ assumes the RAM was previously deselected.

ASYNCHRONOUS TRUTH TABLE

Operation	ZZ	G	I/O Status
Read	L	L	Data Out (DQx)
Read	L	Н	High–Z
Write	L	Х	High–Z
Deselected	L	Х	High–Z
Sleep	Н	Х	High-Z

LINEAR BURST ADDRESS TABLE $(\overline{LBO} = V_{SS})$

1st Address (External)	2nd Address (Internal)	3rd Address (Internal)	4th Address (Internal)
X X00	X X01	X X10	X X11
X X01	X X10	X X11	X X00
X X10	X X11	X X00	X X01
X X11	X X00	X X01	X X10

INTERLEAVED BURST ADDRESS TABLE $(\overline{LBO} = V_{DD})$

1st Address (External)	2nd Address (Internal)	3rd Address (Internal)	4th Address (Internal)
X X00	X X01	X X10	X X11
X X01	X X00	X X11	X X10
X X10	X X11	X X00	X X01
X X11	X X10	X X01	X X00

WRITE TRUTH TABLE

Cycle Type	SGW	sw	SBa	SBb	SBc	SBd
Read	Н	Н	Х	Х	Х	Х
Read	Н	L	Н	Н	Н	Н
Write Byte a	Н	L	L	Н	Н	Н
Write Byte b	Н	L	Н	L	Н	Н
Write Byte c	Н	L	Н	Н	L	Н
Write Byte d	Н	L	Н	Н	Н	L
Write All Bytes	Н	L	L	L	L	L
Write All Bytes	L	Х	Х	Х	Х	Х

ABSOLUTE MAXIMUM RATINGS (See Note 1)

Rating	Symbol	Value	Unit	Notes
Power Supply Voltage	V _{DD}	- 0.5 to + 4.6	V	
Voltage Relative to V _{SS} for Any Pin Except V _{DD}	V _{in} , V _{out}	- 0.5 to V _{DD} + 0.5	V	
Output Current (per I/O)	l _{out}	± 20	mA	
Package Power Dissipation	PD	1.6	W	2
Ambient Temperature	TA	0 to 70	°C	
Die Temperature	TJ	110	°C	2
Temperature Under Bias	T _{bias}	- 10 to 85	°C	
Storage Temperature	T _{stg}	- 55 to 125	°C	

This device contains circuitry to protect the inputs against damage due to high static voltages or electric fields; however, it is advised that normal precautions be taken to avoid application of any voltage higher than maximum rated voltages to this high-impedance

NOTES:

- 1. Permanent device damage may occur if ABSOLUTE MAXIMUM RATINGS are exceeded. Functional operation should be restricted to RECOMMENDED OPER-ATING CONDITIONS. Exposure to higher than recommended voltages for extended periods of time could affect device reliability.
- 2. Power dissipation capability is dependent upon package characteristics and use environment. See Package Thermal Characteristics.

PACKAGE THERMAL CHARACTERISTICS

Rating		Symbol	Max	Unit	Notes
Junction to Ambient (@ 200 lfm)	Single Layer Board Four Layer Board	R _{θJA}	40 25	°C/W	1, 2
Junction to Board (Bottom)		$R_{\theta JB}$	17	°C/W	3
Junction to Case (Top)		$R_{ heta JC}$	9	°C/W	4

NOTES:

- 1. Junction temperature is a function of on-chip power dissipation, package thermal resistance, mounting site (board) temperature, ambient temperature, air flow, board population, and board thermal resistance.
- 2. Per SEMI G38-87.
- 3. Indicates the average thermal resistance between the die and the printed circuit board.
- 4. Indicates the average thermal resistance between the die and the case top surface via the cold plate method (MIL SPEC-883 Method

DC OPERATING CONDITIONS AND CHARACTERISTICS

 $(V_{DD} = 3.3 \text{ V} + 10\%, -5\%, T_{A} = 0 \text{ to } 70^{\circ}\text{C}, \text{ Unless Otherwise Noted})$

RECOMMENDED OPERATING CONDITIONS (Voltages Referenced to V_{SS} = 0 V)

Parameter	Symbol	Min	Тур	Max	Unit
Supply Voltage	V_{DD}	3.135	3.3	3.6	V
Input Low Voltage	VIL	- 0.5	_	0.8	V
Input High Voltage	VIH	2.0	_	V _{DD} + 0.5	V

DC CHARACTERISTICS AND SUPPLY CURRENTS

Parameter		Symbol	Min	Тур	Max	Unit	Notes
Input Leakage Current (0 $V \le V_{in} \le V_{DD}$)		l _{lkg} (I)	_	_	± 1	μΑ	1, 2
Output Leakage Current (0 $V \le V_{in} \le V_{DD}$)	I _{lkg} (O)	_	_	± 1	μΑ		
AC Supply Current (Device Selected, All Outputs Open, Freq = Max, V _{DD} = Max)	MCM63P631A-117 MCM63P631A-100 MCM63P631A-75 MCM63P631A-66	IDDA	_ _ _ _	_ _ _ _	TBD	mA	3, 4, 5
CMOS Standby Supply Current (Device Deselected, Freq = 0, V _{DD} = Max, All Inputs Static at CMOS Levels)		I _{SB2}	_	_	TBD	mA	6, 7
Sleep Mode Supply Current (Sleep Mode, Freq = Max, V_{DD} = Max, All Other Inputs Static at CMOS Levels, $ZZ \ge V_{DD} - 0.2 \text{ V}$)		I _{ZZ}	_	_	2	mA	2, 7, 8
TTL Standby (Device Deselected, Freq = 0, V _{DD} = Max, All Inputs Static at TTL Levels)		I _{SB3}	_	_	TBD	mA	6, 9
Clock Running (Device Deselected, Freq = Max, VDD = Max, All Inputs Toggling at CMOS Levels)	MCM63P631A-117 MCM63P631A-100 MCM63P631A-75 MCM63P631A-66	I _{SB4}	_ _ _ _	_ _ _ _	TBD	mA	6, 7
Static Clock Running (Device Deselected, Freq = Max, VDD = Max, All Inputs Static at TTL Levels)	MCM63P631A-117 MCM63P631A-100 MCM63P631A-75 MCM63P631A-66	I _{SB5}	_ _ _ _	_ _ _ _	TBD	mA	6, 9
Output Low Voltage (I _{OL} = 8 mA)		VoL	_	_	0.4	٧	
Output High Voltage (I _{OH} = -4 mA)		Vон	2.4	_	_	V	

NOTES:

- 1. \overline{LBO} pin has an internal pullup and will exhibit leakage currents of \pm 5 μA .
- 2. ZZ pin has an internal pulldown and will exhibit leakage currents of \pm 5 μ A.
- 3. Reference AC Operating Conditions and Characteristics for input and timing (VIH/VIL, tr/tf, pulse level 0 to 3.0 V).
- 4. All addresses transition simultaneously low (LSB) and then high (MSB).
- 5. Data states are all zero.
- 6. Device in Deselected mode as defined by the Truth Table.
- 7. CMOS levels are $V_{\mbox{in}} \leq V_{\mbox{SS}} + 0.2 \mbox{ V or } \geq V_{\mbox{DD}} 0.2 \mbox{ V}.$
- 8. Device in Sleep Mode as defined by the Asynchronous Truth Table.
- 9. TTL levels are $V_{in} \le V_{IL}$ or $\ge V_{IH}$.

CAPACITANCE (f = 1.0 MHz, dV = 3.0 V, T_A = 0 to 70°C, Periodically Sampled Rather Than 100% Tested)

Parameter	Symbol	Min	Тур	Max	Unit
Input Capacitance	C _{in}	_	3	5	pF
Input/Output Capacitance	C _{I/O}	_	6	8	pF

AC OPERATING CONDITIONS AND CHARACTERISTICS

 $(V_{DD} = 3.3 \text{ V} + 10\%, -5\%, T_{A} = 0 \text{ to } 70^{\circ}\text{C}, \text{ Unless Otherwise Noted})$

READ/WRITE CYCLE TIMING (See Notes 1, 2, 3, and 4)

			1A–117 MHz		IA–100 MHz		1A–75 VIHz	63P63 66 I	1A–66 MHz		
Parameter	Symbol	Min	Max	Min	Max	Min	Max	Min	Max	Unit	Notes
Cycle Time	^t KHKH	8.5	_	10	_	13	_	15	_	ns	
Clock High Pulse Width	^t KHKL	3.4	_	4	_	5.2	_	6	_	ns	
Clock Low Pulse Width	tKLKH	3.4	_	4	_	5.2	_	6	_	ns	
Clock Access Time	^t KHQV	_	4.5	_	4.5	_	7	_	8	ns	
Output Enable to Output Valid	tGLQV	_	4.5	_	4.5	_	5	_	5	ns	
Clock High to Output Active	tKHQX1	0	_	0	_	0	_	0	_	ns	5
Clock High to Output Change	tKHQX2	1.5	_	1.5	_	1.5	_	1.5	_	ns	5
Output Enable to Output Active	tGLQX	0	_	0	_	0	_	0	_	ns	5
Output Disable to Q High–Z	^t GHQZ	_	5.5	_	5.5	_	7	_	8	ns	5, 6
Clock High to Q High–Z	tKHQZ	1.5	5.5	1.5	5.5	2	7	2	8	ns	5, 6
Setup Times: Address ADSP, ADSC, ADV Data In Write Chip Enable	tADKH tADSKH tDVKH tWVKH tEVKH	2.5	_	2.5	_	2.5	_	2.5	_	ns	
Hold Times: Address ADSP, ADSC, ADV Data In Write Chip Enable	[†] KHAX [†] KHADSX [†] KHDX [†] KHWX [†] KHEX	0.5	_	0.5	_	0.5	_	0.5	_	ns	
Sleep Mode Standby	^t ZZS	_	2 x ^t KHKH	_	2 x ^t KHKH		2 x ^t KHKH	_	2 x ^t KHKH	ns	
Sleep Mode Recovery	^t ZZREC	2 x ^t KHKH	_	ns							
Sleep Mode High to Q High–Z	^t ZZQZ		15	_	15		15		15	ns	

NOTES:

- 1. Write applies to all SBx, SW, and SGW signals when the chip is selected and ADSP high.
- 2. Chip Enable applies to all $\overline{SE1}$, $\overline{SE2}$ and $\overline{\overline{SE3}}$ signals whenever \overline{ADSP} or \overline{ADSC} is asserted.
- 3. All read and write cycle timings are referenced from K or \overline{G} .
- 4. \overline{G} is a don't care after write cycle begins. To prevent bus contention, \overline{G} should be negated prior to start of write cycle.
- 5. This parameter is sampled and is not 100% tested.
- 6. Measured at $\pm\,200~\text{mV}$ from steady state.

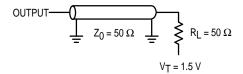


Figure 1. AC Test Load

Note: \overline{E} low = SE2 high and $\overline{SE3}$ low. $\overline{\overline{W}}$ low = \overline{SGW} low and / or \overline{SW} and \overline{SBx} low.

READ/WRITE CYCLES

|▲ DESELECTED ❤ | ← SINGLE READ —

SINGLE READ —

BURSTWRITE

BURSTREAD

NORMAL OPERATION NO READS OR WRITES ALLOWED tZZREC IN SLEEP MODE SLEEP MODE TIMING [2] NO NEW READS OR WRITES ALLOWED tZZQZ tZZS NORMAL OPERATION ADS ADDR ADV ΙШ ∣≥ ß g 22

NOTE: \overline{ADS} low = \overline{ADSC} low or \overline{ADSP} low. \overline{ADS} high = both \overline{ADSC} , \overline{ADSP} high. \overline{E} low = $\overline{SE1}$ low, SE2 high, $\overline{SE3}$ low. IZZ (max) specifications will not be met if inputs toggle.

APPLICATION INFORMATION

The MCM63P631A BurstRAM is a high speed synchronous SRAM intended for use primarily in secondary or level two (L2) cache memory applications. L2 caches are found in a variety of classes of computers — from the desktop personal computer to the high—end servers and transaction processing machines. For simplicity, the majority of L2 caches today are direct mapped and are single bank implementations. These caches tend to be designed for bus speeds in the range of 33 to 66 MHz. At these bus rates, non—pipelined (flow—through) BurstRAMs can be used since their access times meet the speed requirements for a minimum—latency, zero—wait state L2 cache interface. Latency is a measure (time) of "dead" time the memory system exhibits as a result of a memory request.

For those applications that demand bus operation at greater than 66 MHz or multi–bank L2 caches at 66 MHz, the pipelined (register/register) version of the 64K x 32 BurstRAM (MCM63P631A) allows the designer to maintain zero—wait state operation. Multiple banks of BurstRAMs create additional bus loading and can cause the system to otherwise miss its timing requirements. The access time (clock–to–valid–data) of a pipelined BurstRAM is inherently faster than a non–pipelined device by a few nanoseconds. This does not come without cost. The cost is latency — "dead" time.

Since most L2 caches are tied to the processor bus and bus speeds continue to increase over time, pipelined (R/R) BurstRAMs are the best choice in achieving zero–wait state L2 cache performance. For cost–sensitive applications that require zero–wait state L2 cache bus speeds of up to 75 MHz, pipelined BurstRAMs are able to provide fast clock to valid data times required of these high speed buses.

SLEEP MODE

A sleep mode feature, the ZZ pin, has been implemented on the MCM63P631A. It allows the system designer to place the RAM in the lowest possible power condition by asserting ZZ. The sleep mode timing diagram shows the different modes of operation: Normal Operation, No READ/WRITE

Allowed, and Sleep Mode. Each mode has its own set of constraints and conditions that are allowed.

Normal Operation: All inputs must meet setup and hold times prior to sleep and tZZREC nanoseconds after recovering from sleep. Clock (K) must also meet cycle, high, and low times during these periods. Two cycles prior to sleep, initiation of either a read or write operation is not allowed.

No READ/WRITE: During the period of time just prior to sleep and during recovery from sleep, the assertion of either ADSC, ADSP, or any write signal is not allowed. If a write operation occurs during these periods, the memory array may be corrupted. Validity of data out from the RAM can not be guaranteed immediately after ZZ is asserted (prior to being in sleep).

Sleep Mode: The RAM automatically deselects itself. The RAM disconnects its internal clock buffer. The external clock may continue to run without impacting the RAMs sleep current (I_{ZZ}). All inputs are allowed to toggle — the RAM will not be selected and perform any reads or writes. However, if inputs toggle, the I_{ZZ} (max) specification will not be met.

NON-BURST SYNCHRONOUS OPERATION

Although this BurstRAM has been designed for PowerPC—and Pentium—based systems, these SRAMs can be used in other high speed L2 cache or memory applications that do not require the burst address feature. Most L2 caches designed with a synchronous interface can make use of the MCM63P631A. The burst counter feature of the BurstRAM can be disabled, and the SRAM can be configured to act upon a continuous stream of addresses. See Figure 2.

CONTROL PIN TIE VALUES $(H \ge V_{IH}, L \le V_{IL})$

Non-Burst	ADSP	ADSC	ADV	SE1	LBO
Sync Non–Burst, Pipelined SRAM	Н	L	Н	L	Х

NOTE: Although X is specified in the table as a don't care, the pin must be tied either high or low.

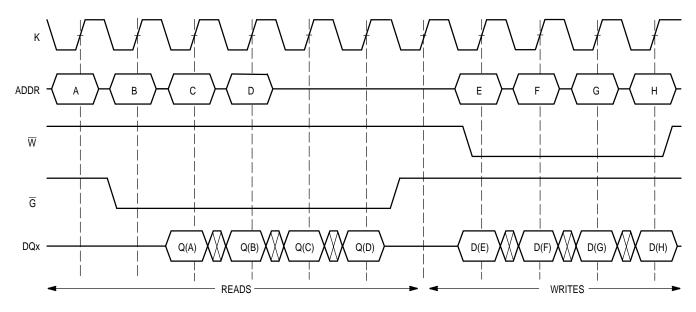
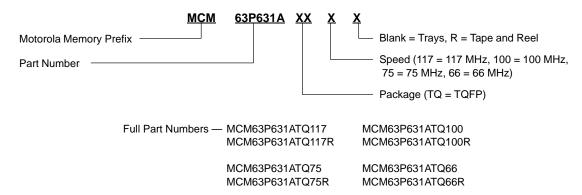


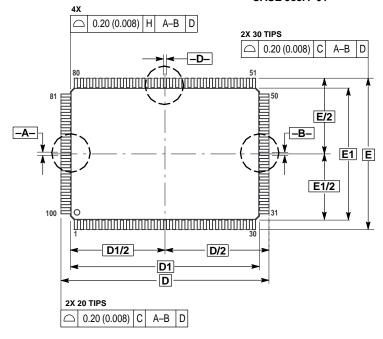
Figure 2. Configured as Non-Burst Pipelined Synchronous SRAM

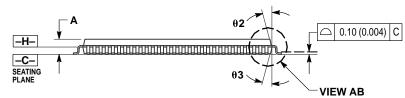
ORDERING INFORMATION (Order by Full Part Number)

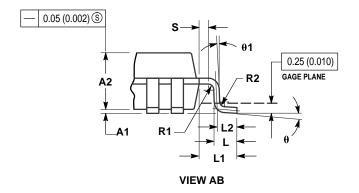


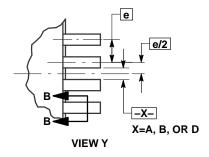
PACKAGE DIMENSIONS

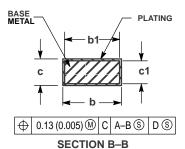
TQ PACKAGE TQFP CASE 983A-01











NOTES:

- DIMENSIONING AND TOLERANCING PER ANSI
- Y14.5M, 1982. CONTROLLING DIMENSION: MILLIMETER.
- DATUM PLANE -H- IS LOCATED AT BOTTOM OF LEAD AND IS COINCIDENT WITH THE LEAD

- LEAD AND IS COINCIDENT WITH THE LEAD
 WHERE THE LEAD EXITS THE PLASTIC BODY AT
 THE BOTTOM OF THE PARTING LINE.

 4. DATUMS -A-, -B- AND -D- TO BE DETERMINED
 AT DATUM PLANE -H-.

 5. DIMENSIONS D AND E TO BE DETERMINED AT
 SEATING PLANE -C-.

 6. DIMENSIONS DI AND E1 DO NOT INCLUDE MOLD
 PROTRUSION. ALLOWABLE PROTRUSION IS 0.25
 (0.010) PER SIDE. DIMENSIONS D1 AND B1 DO
 INCLUDE MOLD MISMATCH AND ARE
 DETERMINED AT DATIM PI AND E-H-. DETERMINED AT DATUM PLANE -H-
- DIMENSION b DOES NOT INCLUDE DAMBAR
 PROTRUSION. DAMBAR PROTRUSION SHALL NOT CAUSE THE b DIMENSION TO EXCEED 0.45 (0.018).

	MILLIN	IETERS	INCHES			
DIM	MIN	MAX	MIN	MAX		
Α		1.60		0.063		
A1	0.05	0.15	0.002	0.006		
A2	1.35	1.45	0.053	0.057		
b	0.22	0.38	0.009	0.015		
b1	0.22	0.33	0.009	0.013		
С	0.09	0.20	0.004	0.008		
c1	0.09	0.16	0.004	0.006		
D	22.00 BSC		0.866 BSC			
D1	20.00	BSC	0.787 BSC			
Е	16.00	BSC	0.630 BSC			
E1	14.00	BSC	0.551 BSC			
e	0.65 BSC		0.026 BSC			
L	0.45	0.75	0.018	0.030		
L1	1.00 REF		0.039 REF			
L2	0.50	0.50 REF		0.020 REF		
S	0.20	-	0.008	_		
R1	0.08		0.003			
R2	0.08	0.20	0.003	0.008		
θ	0°	7°	0°	7°		
θ1	0°		0°			
θ2	11 °	13°	11 °	13°		
θ3	11 °	13°	11 °	13°		

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